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(12) **United States Design Patent**
Fukuoka et al.

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(54) **RADIATION THERMOMETER**

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(**) Term: **14 Years**

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(30) **Foreign Application Priority Data**
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(51) **LOC (9) Cl.** **10-04**

(52) **U.S. Cl.** **D10/57**

(58) **Field of Classification Search** D10/57;
D16/200, 202, 216, 218; 174/50; 220/3.2;
250/201.3; 359/694; 374/121, 126, 130,
374/141, 208; 396/144, 148, 373

See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D594,891 S * 6/2009 Kaplan et al. D16/202

* cited by examiner

Primary Examiner—Antoine D Davis

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(57) **CLAIM**

The ornamental design for a radiation thermometer, as shown and described.

DESCRIPTION

FIG. 1 is a front elevational view of a radiation thermometer showing our new design;

FIG. 2 is a rear elevational view thereof;

FIG. 3 is a left side elevational view thereof;

FIG. 4 is a right side elevational view thereof;

FIG. 5 is a top plan view thereof; and,

FIG. 6 is a bottom plan view thereof.

Portions of the figures that are shown as broken lines are for illustrative purpose only and form no part of the claimed design.

1 Claim, 6 Drawing Sheets

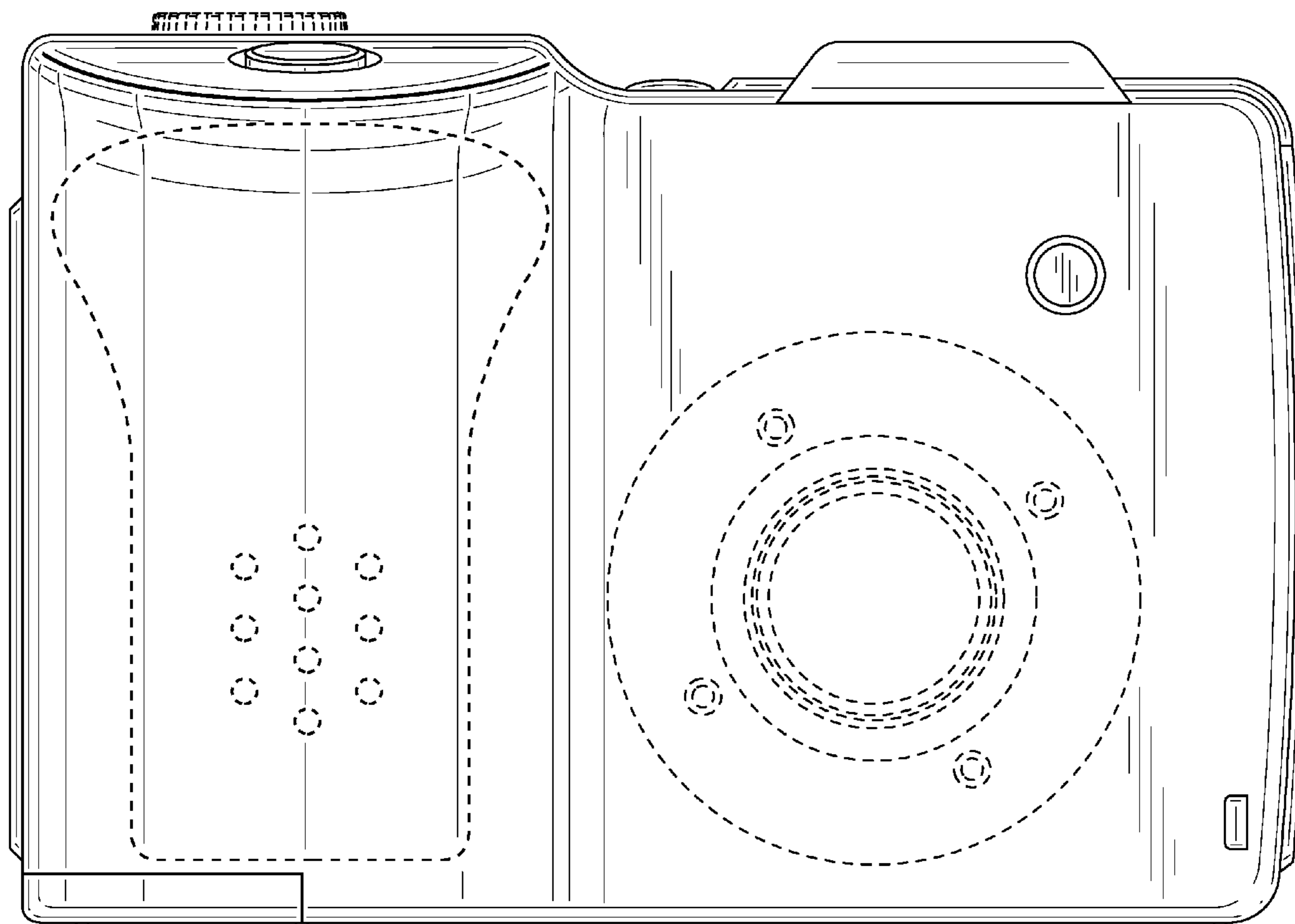


Fig.1

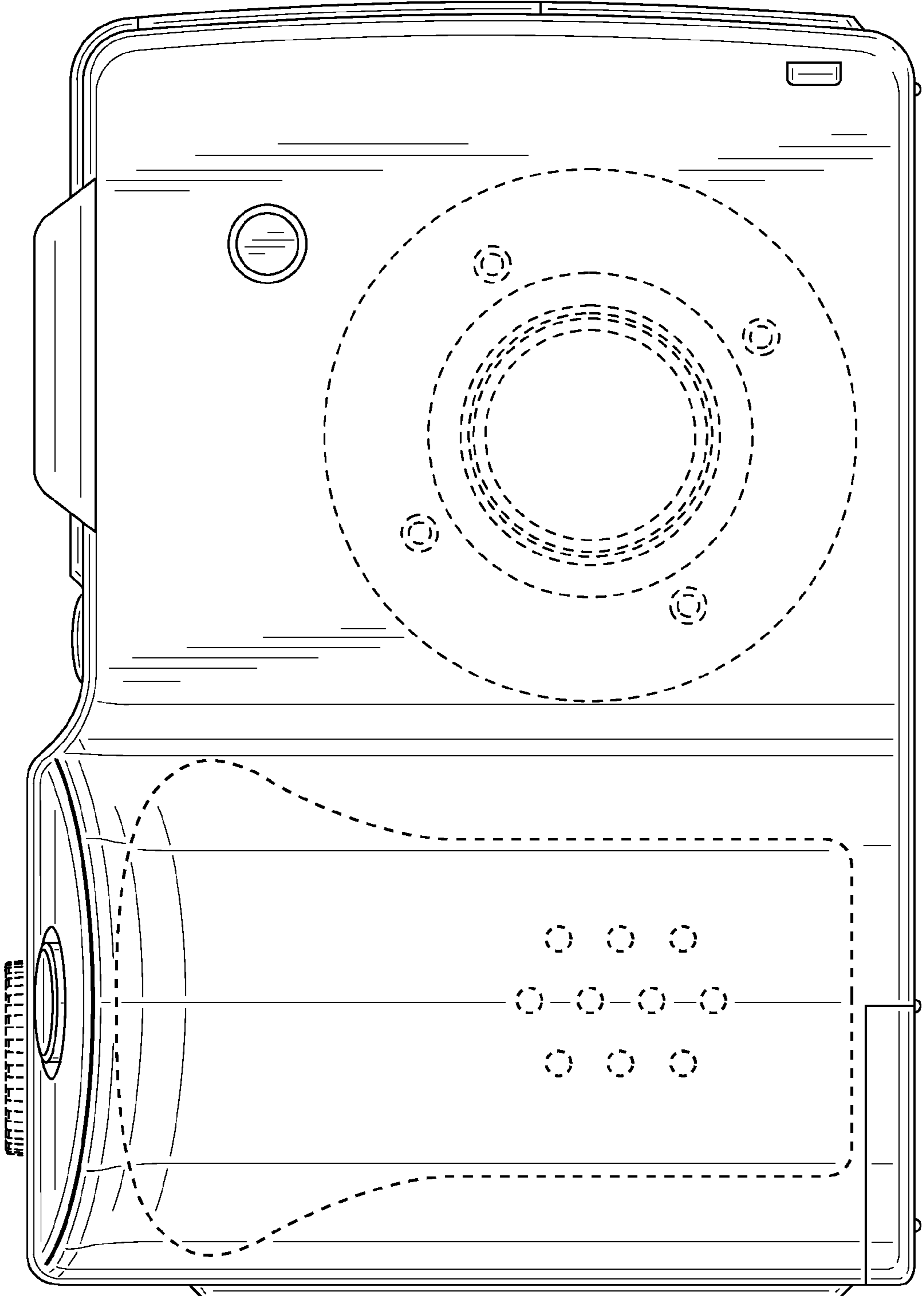


Fig.2

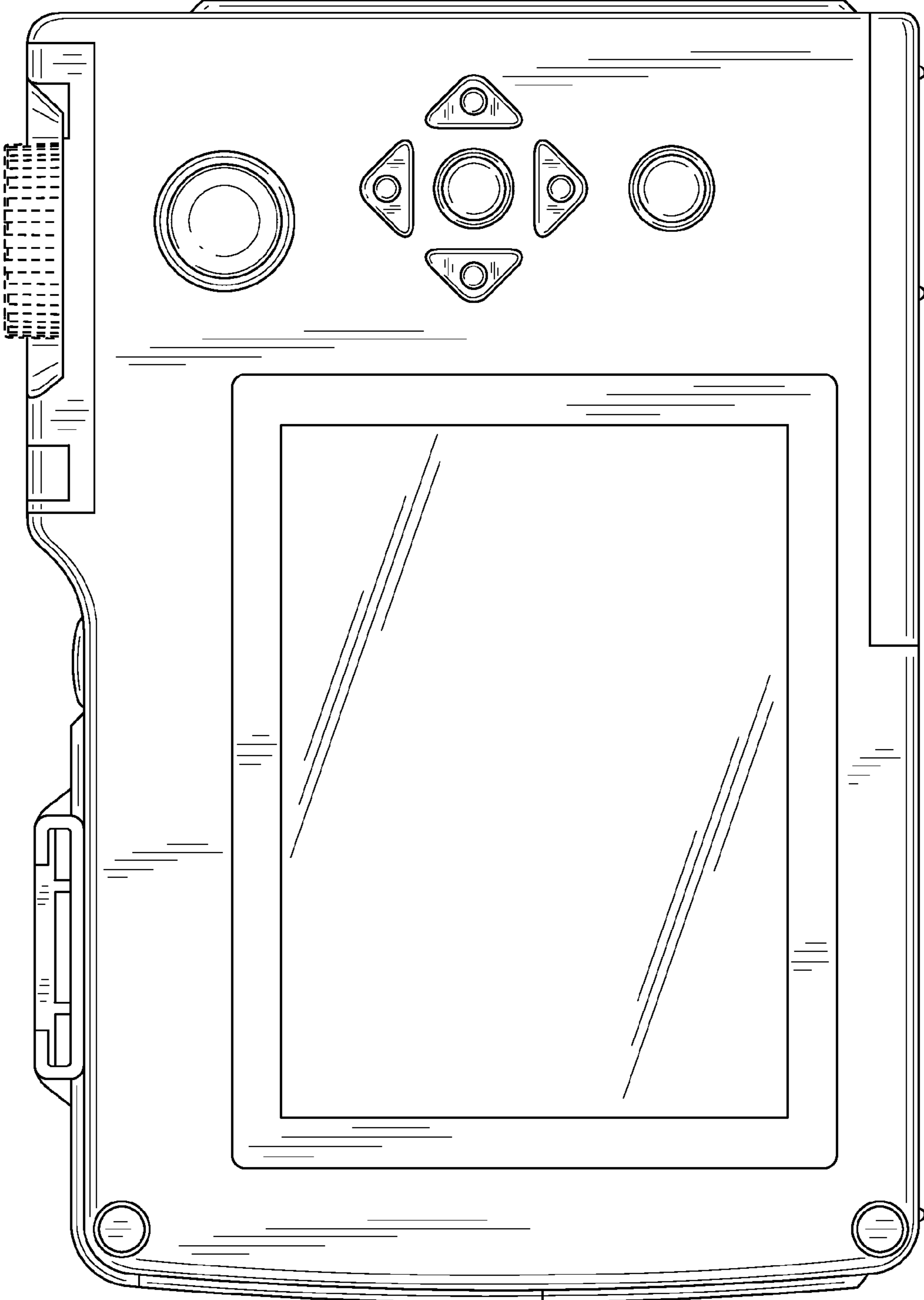


Fig.3

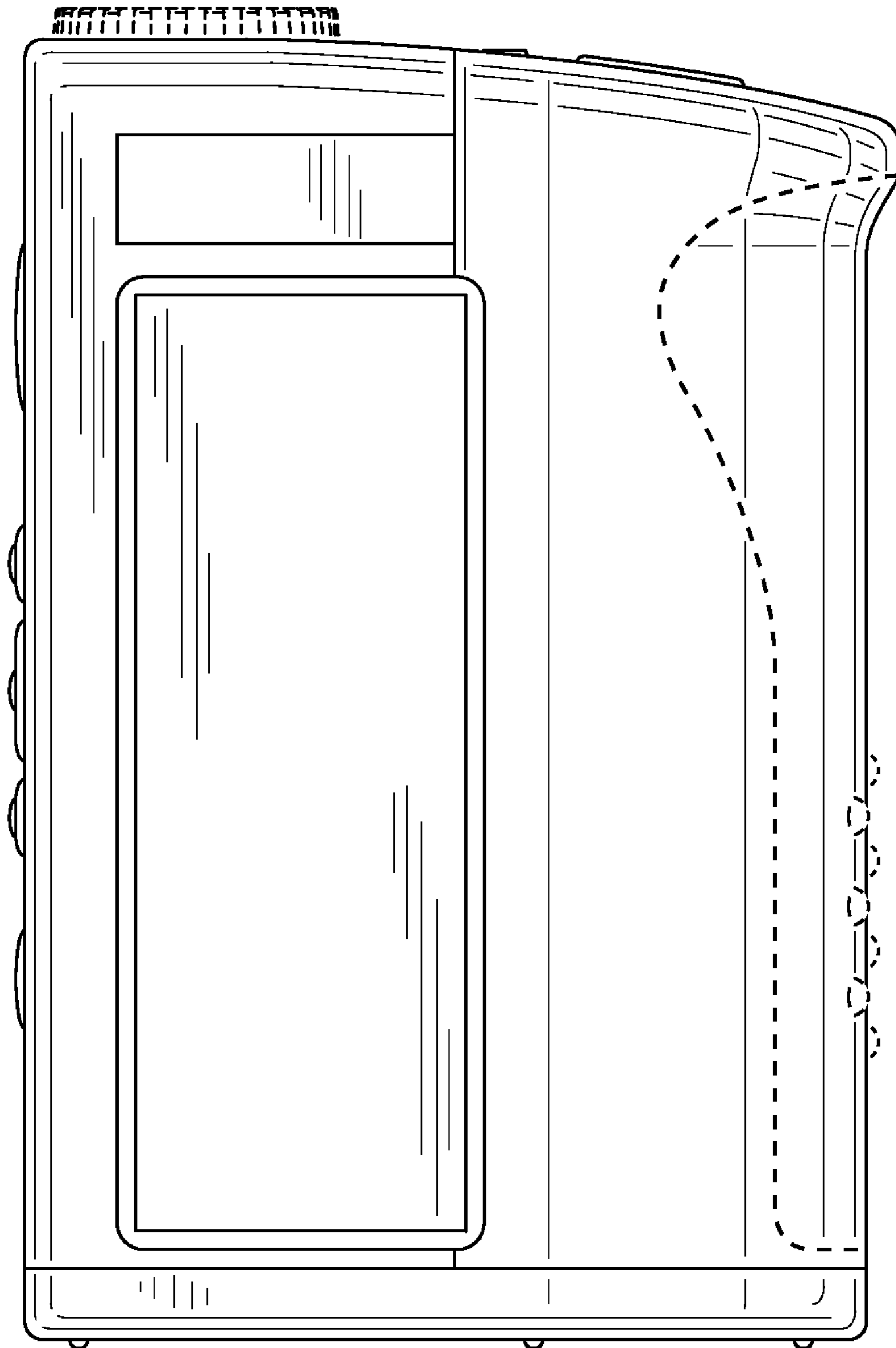


Fig.4

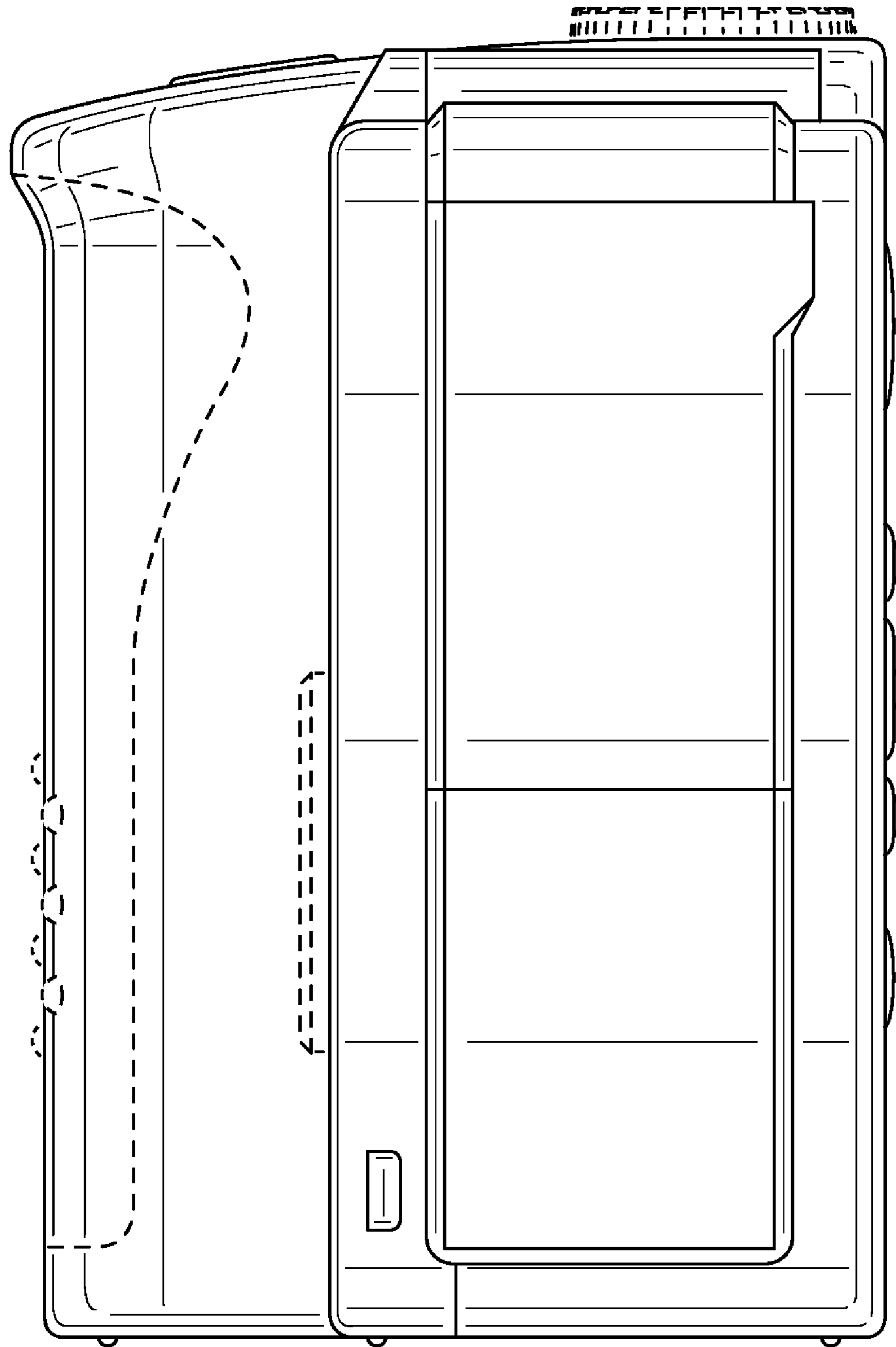


Fig.5

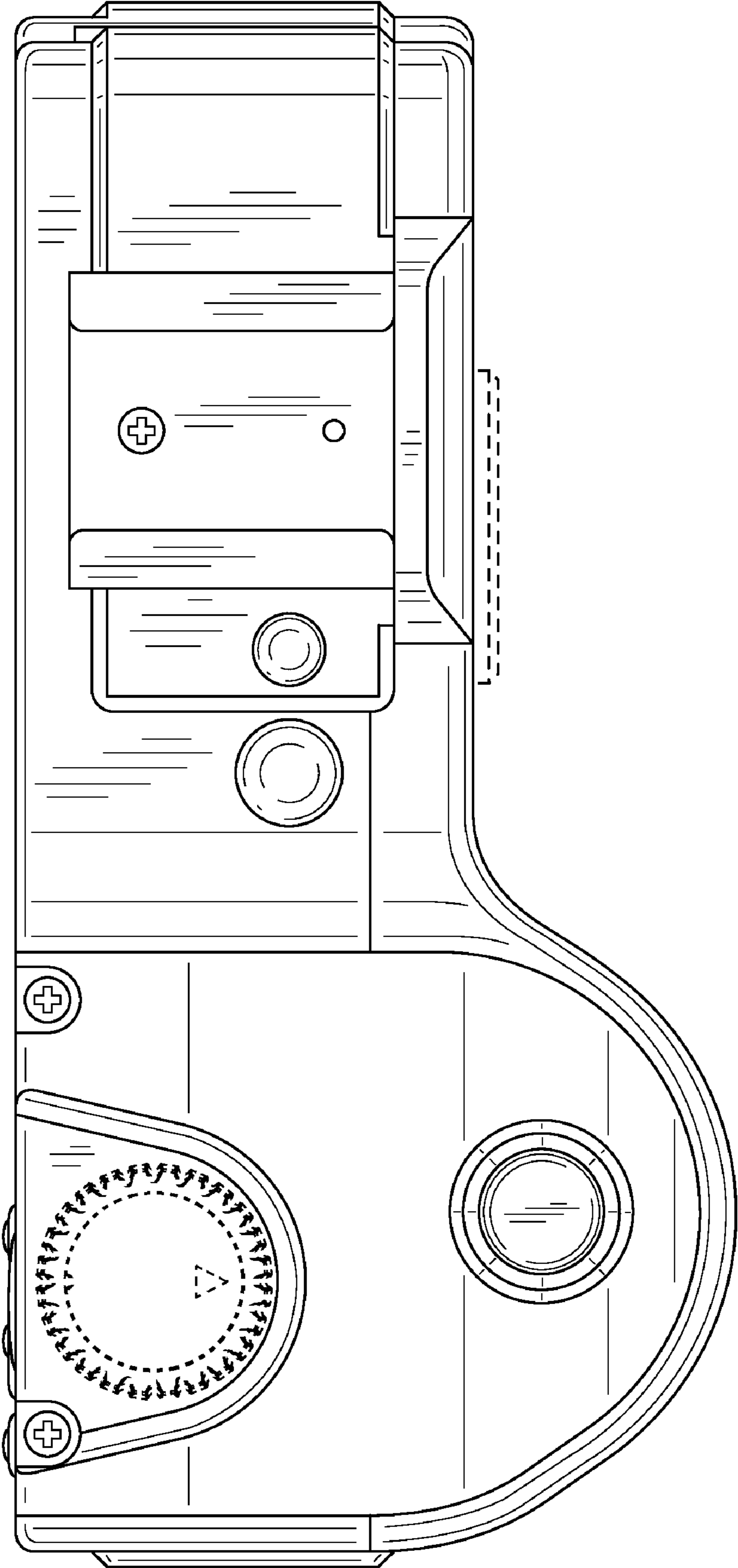


Fig.6

